IRFD113

Vishay Siliconix



HVMDIP

PRODUCT SUMMARY

V_{DS} (V)

R_{DS(on)} (Ω)

Q_{qs} (nC)

Q_{ad} (nC)

Qg (Max.) (nC)

Configuration

Power MOSFET

s

N-Channel MOSFET

0.8

60

7

2

7

Single

 $V_{GS} = 10 V$

FEATURES

- · For automatic insertion
- Compact plastic package
- End stackable
- · Fast switching
- Low drive current
- Easily paralleled
- Excellent temperature stability
- Material categorization: for definitions of compliance please see <u>www.vishay.com/doc?99912</u>

DESCRIPTION

The HVMDIP technology is the key to Vishay's advanced line of power MOSFET transistors. The efficient geometry and unique processing of the HVMDIP design achieves very low on-state resistance combined with high transconductance and extreme device ruggedness. HVMDIPs feature all of the established advantages of MOSFETs such as voltage control, very fast switching, ease of paralleling, and temperature stability of the electrical parameters.

The HVMDIP 4 pin, dual-in-line package brings the advantages of HVMDIPs to high volume applications where automatic PC board insertion is desireable, such as circuit boards for computers, printers, telecommunications equipment, and consumer products. Their compatibility with automatic insertion equipment, low-profile and end stackable features represent the stat-of-the-art in power device packaging.

ORDERING INFORMATION			
Package	HVMDIP		
Lead (Pb)-free	IRFD113PbF		

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-source Voltage ^a			V _{DS}	60	- V	
Gate-source voltage	rce voltage			± 20		
Continuous drain current	V _{GS} at 10 V	T _C = 25 °C	Ι _D	0.8	•	
Pulsed drain current ^b			I _{DM}	6.4	A	
Linear derating factor				0.008	W/°C	
Inductive current, clamped	L = 100 µH		I _{LM}	6.4	А	
Maximum power dissipation	T _C = 25 °C		PD	1.0	W	
Operating junction and storage temperature range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering recommendations (peak temperature)	for 10 s			300 ^c	7	

Notes

a. $T_J = 25 \degree C$ to 150 $\degree C$

b. Repetitive rating; pulse width limited by maximum junction temperature

c. 1.6 mm from case

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THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	120	°C/W		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					•	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$		60	-	-	V
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$		-	4.0	V
Gate-Source Leakage	I _{GSS}	$V_{GS} = \pm 20 V$		-	-	± 500	nA
		V_{DS} = max. rating, V_{GS} = 0 V		-	-	250	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = max. ratii	V_{DS} = max. rating x 0.8, V_{GS} = 0 V, T_C = 125 °C		-	1000	μA
On-State Drain Current ^b	I _{D(on)}	$V_{GS} = 10 V$	$V_{DS} > I_{D(on)} \times R_{DS(on)} \max$.	0.8	-	-	Α
Drain-Source On-State Resistance ^b	R _{DS(on)}	V _{GS} = 10 V	I _D = 0.8 A	-	0.6	0.8	Ω
Forward Transconductanceb	9 _{fs}	$V_{DS} > I_{D(on)} \times R_{DS(on)} \max., I_D = 0.8 \text{ A}$		0.8	1.2	-	S
Dynamic					•	•	
Input Capacitance	C _{iss}	$V_{GS} = 0 V,$		-	135	200	pF
Output Capacitance	C _{oss}		$V_{DS} = 25 V,$		80	100	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz		-	20	25	
Total Gate Charge	Qg			-	5	7	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 \text{ V} \qquad I_D = 4 \text{ A}, \\ V_{DS} = 0.8 \text{ max. rating}$	-	2	-	nC
Gate-Drain Charge	Q _{gd}			-	7	-	
Turn-On Delay Time	t _{d(on)}			-	10	20	– ns
Rise Time	t _r	V _{DD} =	$V_{DD} = 0.5 V_{DS}$, $I_{D} = 0.8 A$,		15	25	
Turn-Off Delay Time	t _{d(off)}	$R_g = 50 \Omega$		-	15	25	
Fall Time	t _f			-	10	20	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.0	-	
Internal Source Inductance	L _S			-	6.0	-	nH
Drain-Source Body Diode Characteristic	S				•	•	
Continuous Source-Drain Diode Current	IS	MOSFET symbol showing the integral reverse p - n junction diode		-	-	0.8	
Pulsed Diode Forward Current	I _{SM}			-	-	6.4	A
Body Diode Voltage ^a	V _{SD}	$T_A = 25 \text{ °C}, I_S = 0.8 \text{ A}, V_{GS} = 0 \text{ V}$		-	-	2	V
Body Diode Reverse Recovery Time	t _{rr}	$T_{\rm J} = 150 ^{\circ}\text{C}, I_{\rm F} = 1.0 \text{A}, \text{dl/dt} = 100 \text{A/}\mu\text{s}$		-	100	-	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.2	-	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-o		on is dom	inated by	Ls and L	_n)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11)

b. Pulse width \leq 300 µs; duty cycle \leq 2 %

2



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

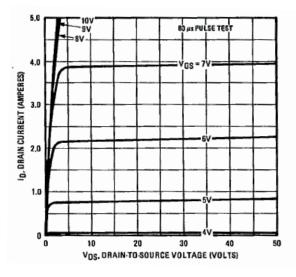


Fig. 1 - Typical Output Characteristics

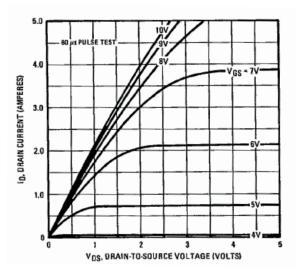


Fig. 2 - Typical Saturation Characteristics

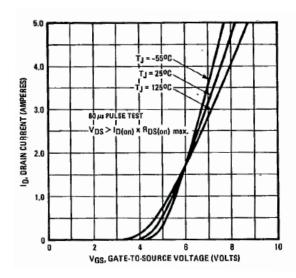


Fig. 1 - Typical Transfer Characteristics

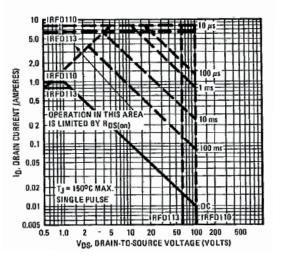


Fig. 3 - Maximum Safe Operatung Area





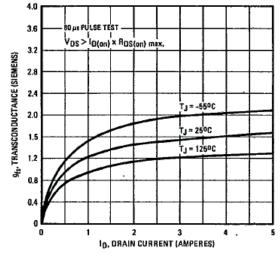


Fig. 4 - Typical Transconductance vs. Drain Current

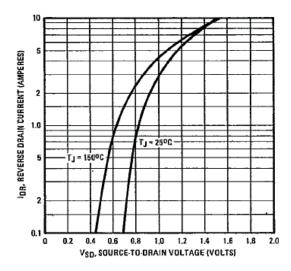


Fig. 5 - Typical Source-Drain Diode Forward Voltage

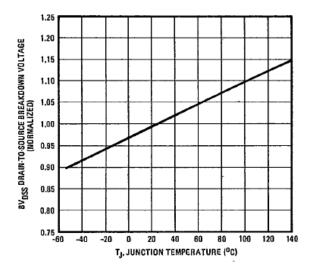


Fig. 6 - Breakdown Voltage vs. Temperature

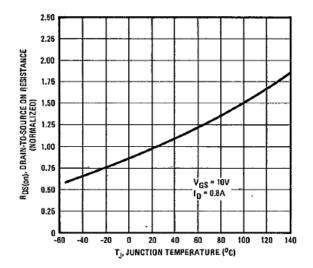


Fig. 7 - Normalized On-Resistance vs. Temperature

4

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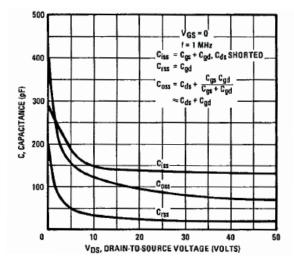


Fig. 8 - Typical Capacitance vs. Drain-to-Source Voltage

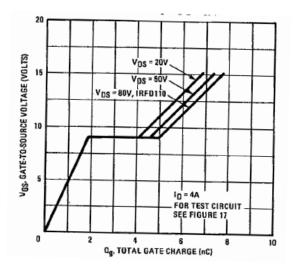


Fig. 9 - Typical Gate Charge vs. Gate-to-Source Voltage

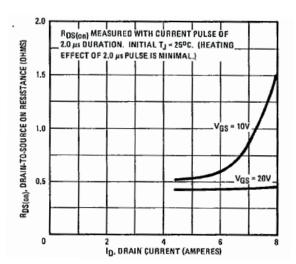


Fig. 10 - Typical On-Resistance vs. Darin Current

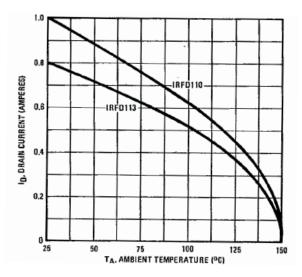
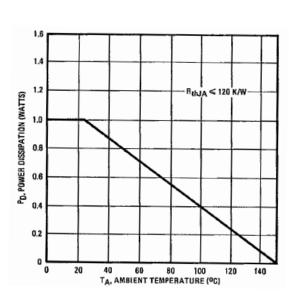


Fig. 11 - Maximum Darin Current vs. Case Temperature

5

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Fig. 12 - Power vs. Temperature Derating

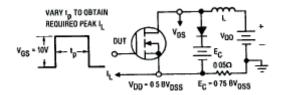


Fig. 13 - Clamped Inductive Test Circuit

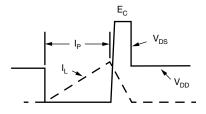


Fig. 14 - Clamped Inductive Waveforms

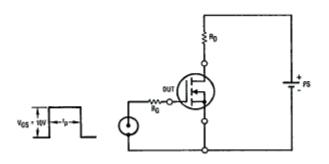


Fig. 15 - Switching Time Test Circuit

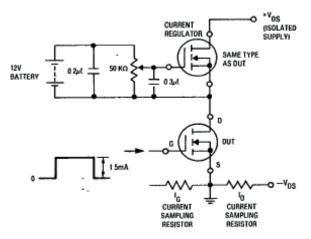
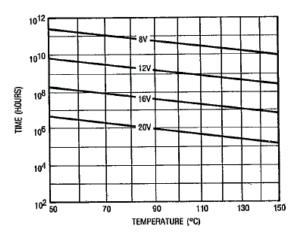
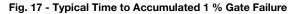
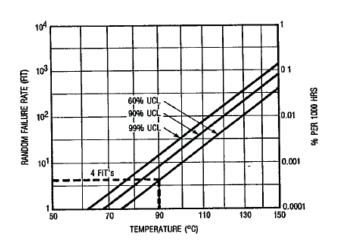


Fig. 16 - Gate Charge Test Circuit

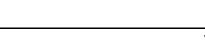








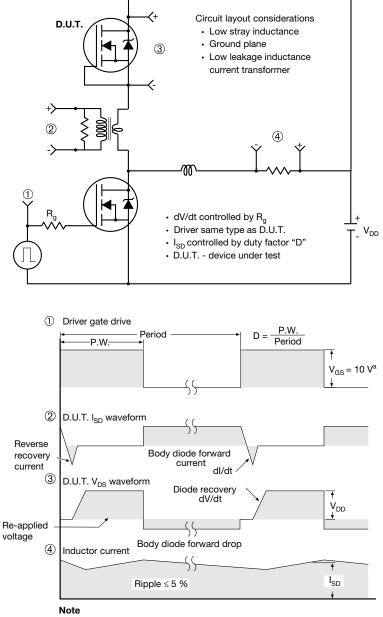
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Peak Diode Recovery dV/dt Test Circuit



a. $V_{GS} = 5 V$ for logic level devices

Fig. 19 - For N-Channel

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1